

ABSTRACT OF THE DISCLOSURE

Capacitance generated by a dummy pattern can be reduced without lowering wiring density by arranging the dummy pattern on one wiring layer in a manner responding to an actual pattern or the dummy pattern on the other wiring layer, whereby at least one of the following can be improved: distances between dummy patterns on different wiring layers, overlapped areas of dummy patterns, and such side length of the dummy pattern as opposed to the actual pattern on the same wiring layer.